

Search Notes

Application/Control No.

10/664,687

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

BYBEE ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	updated	12/6/2005	<i>mm</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPGPUB text search (see attached)	12/6/2005	<i>mm</i> SWH